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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details	
Product Status	Active
Number of LABs/CLBs	65340
Number of Logic Elements/Cells	1143450
Total RAM Bits	82329600
Number of I/O	516
Number of Gates	-
Voltage - Supply	0.698V ~ 0.876V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 100°C (TJ)
Package / Case	1156-BBGA, FCBGA
Supplier Device Package	1156-FCBGA (35x35)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xcku15p-l2ffva1156e

Table 2: **Recommended Operating Conditions[1][2]** ***(Cont'd)***

Symbol	Description	Min	Typ	Max	Units
GTH or GTY Transceiver					
$V_{MGTAVCC}$[10]	Analog supply voltage for the GTH or GTY transceiver.	0.873	0.900	0.927	V
$V_{MGTAVTT}$[10]	Analog supply voltage for the GTH or GTY transmitter and receiver termination circuits.	1.164	1.200	1.236	V
$V_{MGTVCCAUX}$[10]	Auxiliary analog QPLL voltage supply for the transceivers.	1.746	1.800	1.854	V
$V_{MGTAVTTRCAL}$[10]	Analog supply voltage for the resistor calibration circuit of the GTH or GTY transceiver column.	1.164	1.200	1.236	V
SYSMON					
V_{CCADC}	SYSMON supply relative to GNDADC.	1.746	1.800	1.854	V
V_{REFP}	SYSMON externally supplied reference voltage relative to GNDADC.	1.200	1.250	1.300	V
Temperature					
T_j[12]	Junction temperature operating range for extended (E) temperature devices.[11]	0	–	100	°C
	Junction temperature operating range for industrial (I) temperature devices.	–40	–	100	°C
	Junction temperature operating range for eFUSE programming.[13]	–40	–	125	°C

Notes:

1. All voltages are relative to GND.
2. For the design of the power distribution system consult *UltraScale Architecture PCB Design Guide* (UG583).
3. V_{CCINT_IO} must be connected to V_{CCBRAM}.
4. For V_{CCO_0}, the minimum recommended operating voltage for power on and during configuration is 1.425V. After configuration, data is retained even if V_{CCO} drops to 0V.
5. Includes V_{CCO} of 1.0V (HP I/O only), 1.2V, 1.35V, 1.5V, 1.8V, 2.5V (HD I/O only) at ±5%, and 3.3V (HD I/O only) at +3/–5%.
6. V_{CCAUX_IO} must be connected to V_{CCAUX}.
7. The lower absolute voltage specification always applies.
8. A total of 200 mA per bank should not be exceeded.
9. If battery is not used, connect V_{BATT} to either GND or V_{CCAUX}.
10. Each voltage listed requires filtering as described in *UltraScale Architecture GTH Transceiver User Guide* (UG576) or *UltraScale Architecture GTY Transceiver User Guide* (UG578).
11. Devices labeled with the speed/temperature grade of -2LE normally operate under Extended (E) temperature grade specifications with a maximum junction temperature of 100°C. However, E temperature grade devices can operate for a for a limited time at a junction temperature of 110°C. Timing parameters adhere to the same speed file at 110°C as they do at 100°C, regardless of operating voltage (nominal voltage of 0.85V or a low-voltage of 0.72V). Operation at Tj = 110°C is limited to 1% of the device lifetime and can occur sequentially or at regular intervals as long as the total time does not exceed 1% of the device lifetime.
12. Xilinx recommends measuring the Tj of a device using the system monitor as described in the *UltraScale Architecture System Monitor User Guide* (UG580). The SYSMON temperature measurement errors (that are described in Table 76) must be accounted for in your design. For example, by using an external reference of 1.25V, when SYSMON reports 97°C, there is a measurement error ±3°C. A reading of 97°C is considered the maximum adjusted Tj (100°C – 3°C = 97°C).
13. Do not program eFUSE during device configuration (e.g., during configuration, during configuration readback, or when readback CRC is active).

Table 14: **Complementary Differential SelectIO DC Input and Output Levels for HP I/O Banks[(1)]**

I/O Standard	V_{ICM} (V)[(2)]			V_{ID} (V)[(3)]		V_{OL} (V)[(4)]	V_{OH} (V)[(5)]	I_{OL}	I_{OH}
	Min	Typ	Max	Min	Max	Max	Min	mA	mA
DIFF_HSTL_I	0.680	$V_{CCO}/2$	$(V_{CCO}/2) + 0.150$	0.100	–	0.400	$V_{CCO} - 0.400$	5.8	–5.8
DIFF_HSTL_I_12	0.400 x V_{CCO}	$V_{CCO}/2$	0.600 x V_{CCO}	0.100	–	0.250 x V_{CCO}	0.750 x V_{CCO}	4.1	–4.1
DIFF_HSTL_I_18	$(V_{CCO}/2) - 0.175$	$V_{CCO}/2$	$(V_{CCO}/2) + 0.175$	0.100	–	0.400	$V_{CCO} - 0.400$	6.2	–6.2
DIFF_HSUL_12	$(V_{CCO}/2) - 0.120$	$V_{CCO}/2$	$(V_{CCO}/2) + 0.120$	0.100	–	20% V_{CCO}	80% V_{CCO}	0.1	–0.1
DIFF_SSTL12	$(V_{CCO}/2) - 0.150$	$V_{CCO}/2$	$(V_{CCO}/2) + 0.150$	0.100	–	$(V_{CCO}/2) - 0.150$	$(V_{CCO}/2) + 0.150$	8.0	–8.0
DIFF_SSTL135	$(V_{CCO}/2) - 0.150$	$V_{CCO}/2$	$(V_{CCO}/2) + 0.150$	0.100	–	$(V_{CCO}/2) - 0.150$	$(V_{CCO}/2) + 0.150$	9.0	–9.0
DIFF_SSTL15	$(V_{CCO}/2) - 0.175$	$V_{CCO}/2$	$(V_{CCO}/2) + 0.175$	0.100	–	$(V_{CCO}/2) - 0.175$	$(V_{CCO}/2) + 0.175$	10.0	–10.0
DIFF_SSTL18_I	$(V_{CCO}/2) - 0.175$	$V_{CCO}/2$	$(V_{CCO}/2) + 0.175$	0.100	–	$(V_{CCO}/2) - 0.470$	$(V_{CCO}/2) + 0.470$	7.0	–7.0

Notes:

1. DIFF_POD10 and DIFF_POD12 HP I/O bank specifications are shown in Table 15, Table 16, and Table 17.
2. V_{ICM} is the input common mode voltage.
3. V_{ID} is the input differential voltage.
4. V_{OL} is the single-ended low-output voltage.
5. V_{OH} is the single-ended high-output voltage.

Table 15: **DC Input Levels for Differential POD10 and POD12 I/O Standards[(1)(2)]**

I/O Standard	V_{ICM} (V)			V_{ID} (V)	
	Min	Typ	Max	Min	Max
DIFF_POD10	0.63	0.70	0.77	0.14	–
DIFF_POD12	0.76	0.84	0.92	0.16	–

Notes:

1. Tested according to relevant specifications.
2. Standards specified using the default I/O standard configuration. For details, see the *UltraScale Architecture SelectIO Resources User Guide* (UG571).

Table 16: **DC Output Levels for Single-ended and Differential POD10 and POD12 Standards[(1)(2)]**

Symbol	Description	V_{OUT}	Min	Typ	Max	Units
R_{OL}	Pull-down resistance.	V_{OM_DC} (as described in Table 17)	36	40	44	Ω
R_{OH}	Pull-up resistance.	V_{OM_DC} (as described in Table 17)	36	40	44	Ω

Notes:

1. Tested according to relevant specifications.
2. Standards specified using the default I/O standard configuration. For details, see the *UltraScale Architecture SelectIO Resources User Guide* (UG571).

Table 17: **Table 16 Definitions for DC Output Levels for POD Standards**

Symbol	Description	All Speed Grades	Units
V_{OM_DC}	DC output Mid measurement level (for IV curve linearity).	0.8 x V_{CCO}	V

AC Switching Characteristics

All values represented in this data sheet are based on the speed specifications in the Vivado® Design Suite as outlined in Table 20.

Table 20: **Speed Specification Version By Device**

2017.1	Device
1.08	XCKU11P
1.10	XCKU3P, XCKU5P, XCKU9P, XCKU13P, and XCKU15P

Switching characteristics are specified on a per-speed-grade basis and can be designated as Advance, Preliminary, or Production. Each designation is defined as follows:

Advance Product Specification

These specifications are based on simulations only and are typically available soon after device design specifications are frozen. Although speed grades with this designation are considered relatively stable and conservative, some under-reporting might still occur.

Preliminary Product Specification

These specifications are based on complete ES (engineering sample) silicon characterization. Devices and speed grades with this designation are intended to give a better indication of the expected performance of production silicon. The probability of under-reporting delays is greatly reduced as compared to Advance data.

Product Specification

These specifications are released once enough production silicon of a particular device family member has been characterized to provide full correlation between specifications and devices over numerous production lots. There is no under-reporting of delays, and customers receive formal notification of any subsequent changes. Typically, the slowest speed grades transition to production before faster speed grades.

Testing of AC Switching Characteristics

Internal timing parameters are derived from measuring internal test patterns. All AC switching characteristics are representative of worst-case supply voltage and junction temperature conditions.

For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer and back-annotate to the simulation net list. Unless otherwise noted, values apply to all Kintex UltraScale+ FPGAs.

Production Silicon and Software Status

In some cases, a particular family member (and speed grade) is released to production before a speed specification is released with the correct label (Advance, Preliminary, Production). Any labeling discrepancies are corrected in subsequent speed specification releases.

Table 22 lists the production released Kintex UltraScale+ FPGAs, speed grade, and the minimum corresponding supported speed specification version and Vivado software revisions. The Vivado software and speed specifications listed are the minimum releases required for production. All subsequent releases of software and speed specifications are valid.

Table 22: **Kintex UltraScale+ FPGA Device Production Software and Speed Specification Release**

Device	Speed Grade and V_{CCINT} Operating Voltages						
	0.90V	0.85V				0.72V	
	-3	-2	-1	-2L	-1L	-2L	-1L
XCKU3P		Vivado tools 2017.1 v1.10					
XCKU5P		Vivado tools 2017.1 v1.10					
XCKU9P							
XCKU11P							
XCKU13P							
XCKU15P							

Notes:

1. Blank entries indicate a device and/or speed grade in Advance or Preliminary status.

FPGA Logic Performance Characteristics

This section provides the performance characteristics of some common functions and designs implemented in Kintex UltraScale+ FPGAs. These values are subject to the same guidelines as the AC Switching Characteristics, page 16. In each table, the I/O bank type is either high performance (HP) or high density (HD).

Table 23: **LVDS Component Mode Performance**

Description	I/O Bank Type	Speed Grade and V_{CCINT} Operating Voltages										Units
		0.90V		0.85V				0.72V				
		-3		-2		-1		-2		-1		
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
LVDS TX DDR (OSERDES 4:1, 8:1)	HP	0	1250	0	1250	0	1250	0	1250	0	1250	Mb/s
LVDS TX SDR (OSERDES 2:1, 4:1)	HP	0	625	0	625	0	625	0	625	0	625	Mb/s
LVDS RX DDR (ISERDES 1:4, 1:8)[1]	HP	0	1250	0	1250	0	1250	0	1250	0	1250	Mb/s
LVDS RX DDR	HD	0	250	0	250	0	250	0	250	0	250	Mb/s
LVDS RX SDR (ISERDES 1:2, 1:4)[1]	HP	0	625	0	625	0	625	0	625	0	625	Mb/s
LVDS RX SDR	HD	0	125	0	125	0	125	0	125	0	125	Mb/s

Notes:

1. LVDS receivers are typically bounded with certain applications to achieve maximum performance. Package skews are not included and should be removed through PCB routing.

Table 24: **LVDS Native Mode Performance[(1)(2)]**

Description	DATA_WIDTH	I/O Bank Type	Speed Grade and V_{CCINT} Operating Voltages										Units
			0.90V		0.85V				0.72V				
			-3		-2		-1		-2		-1		
			Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
LVDS TX DDR (TX_BITSLICE)	4	HP	375	1600	375	1600	375	1260	375	1400	375	1260	Mb/s
	8		375	1600	375	1600	375	1260	375	1600	375	1260	Mb/s
LVDS TX SDR (TX_BITSLICE)	4	HP	187.5	800	187.5	800	187.5	630	187.5	700	187.5	630	Mb/s
	8		187.5	800	187.5	800	187.5	630	187.5	800	187.5	630	Mb/s
LVDS RX DDR (RX_BITSLICE)[(3)]	4	HP	375	1600	375	1600	375	1260	375	1400	375	1260	Mb/s
	8		375	1600	375	1600	375	1260	375	1600	375	1260	Mb/s
LVDS RX SDR (RX_BITSLICE)[(3)]	4	HP	187.5	800	187.5	800	187.5	630	187.5	700	187.5	630	Mb/s
	8		187.5	800	187.5	800	187.5	630	187.5	800	187.5	630	Mb/s

Notes:

1. Native mode is supported through the High-Speed SelectIO Interface Wizard available with the Vivado Design Suite. The performance values assume a source-synchronous interface.
2. PLL settings can restrict the minimum allowable data rate. For example, when using the PLL with CLKOUTPHY_MODE = VCO_HALF the minimum frequency is PLL_FVCOMIN/2.
3. LVDS receivers are typically bounded with certain applications to achieve maximum performance. Package skews are not included and should be removed through PCB routing.

Table 25: **MIPI D-PHY Performance**

Description	I/O Bank Type	Speed Grade and V_{CCINT} Operating Voltages					Units
		0.90V	0.85V		0.72V		
		-3	-2	-1	-2	-1	
MIPI D-PHY transmitter or receiver.	HP	1500	1500	1260	1260	1260	Mb/s

Table 26: **LVDS Native-Mode 1000BASE-X Support(1)**

Description	I/O Bank Type	Speed Grade and V_{CCINT} Operating Voltages				
		0.90V	0.85V		0.72V	
		-3	-2	-1	-2	-1
1000BASE-X	HP	Yes				

Notes:

1. 1000BASE-X support is based on the *IEEE Standard for CSMA/CD Access Method and Physical Layer Specifications* (IEEE Std 802.3-2008).

Table 27 provides the maximum data rates for applicable memory standards using the Kintex UltraScale+ FPGA memory PHY. Refer to Memory Interfaces for the complete list of memory interface standards supported and detailed specifications. The final performance of the memory interface is determined through a complete design implemented in the Vivado Design Suite, following guidelines in the *UltraScale Architecture PCB Design Guide* (UG583), electrical analysis, and characterization of the system.

Table 27: **Maximum Physical Interface (PHY) Rate for Memory Interfaces**

Memory Standard	Package	DRAM Type	Speed Grade and V_{CCINT} Operating Voltages					Units
			0.90V	0.85V		0.72V		
			-3	-2	-1	-2	-1	
DDR4	All FFV packages	Single rank component	2666	2666	2400	2400	2133	Mb/s
		1 rank DIMM(1)(2)(3)	2400	2400	2133	2133	1866	Mb/s
		2 rank DIMM(1)(4)	2133	2133	1866	1866	1600	Mb/s
		4 rank DIMM(1)(5)	1600	1600	1333	1333	N/A	Mb/s
	SFVB784	Single rank component	2400	2400	2133	2133	1866	Mb/s
		1 rank DIMM(1)(2)	2133	2133	1866	1866	1600	Mb/s
		2 rank DIMM(1)(4)	1866	1866	1600	1600	1600	Mb/s
DDR3	All FFV packages	Single rank component	2133	2133	2133	2133	1866	Mb/s
		1 rank DIMM(1)(2)	1866	1866	1866	1866	1600	Mb/s
		2 rank DIMM(1)(4)	1600	1600	1600	1600	1333	Mb/s
		4 rank DIMM(1)(5)	1066	1066	1066	1066	800	Mb/s
	SFVB784	Single rank component	1866	1866	1866	1866	1600	Mb/s
		1 rank DIMM(1)(2)	1600	1600	1600	1600	1600	Mb/s
		2 rank DIMM(1)(4)	1600	1600	1600	1600	1333	Mb/s
		4 rank DIMM(1)(5)	1066	1066	1066	1066	800	Mb/s

FPGA Logic Switching Characteristics

Table 28 (high-density IOB (HD)) and Table 29 (high-performance IOB (HP)) summarizes the values of standard-specific data input delay adjustments, output delays terminating at pads (based on standard) and 3-state delays.

- $T_{INBUF\_DELAY\_PAD\_I}$ is the delay from IOB pad through the input buffer to the I-pin of an IOB pad. The delay varies depending on the capability of the SelectIO input buffer.
- $T_{OUTBUF\_DELAY\_O\_PAD}$ is the delay from the O pin to the IOB pad through the output buffer of an IOB pad. The delay varies depending on the capability of the SelectIO output buffer.
- $T_{OUTBUF\_DELAY\_TD\_PAD}$ is the delay from the T pin to the IOB pad through the output buffer of an IOB pad, when 3-state is disabled. The delay varies depending on the SelectIO capability of the output buffer. In HP I/O banks, the internal DCI termination turn-on time is always faster than $T_{OUTBUF\_DELAY\_TD\_PAD}$ when the DCITERMDISABLE pin is used. In HD I/O banks, the on-die termination turn-on time is always faster than $T_{OUTBUF\_DELAY\_TD\_PAD}$ when the INTERMDISABLE pin is used.

IOB High Density (HD) Switching Characteristics

Table 28: **IOB High Density (HD) Switching Characteristics**

I/O Standards	$T_{INBUF\_DELAY\_PAD\_I}$					$T_{OUTBUF\_DELAY\_O\_PAD}$					$T_{OUTBUF\_DELAY\_TD\_PAD}$					Units
	0.90V	0.85V		0.72V		0.90V	0.85V		0.72V		0.90V	0.85V		0.72V		
	-3	-2	-1	-2	-1	-3	-2	-1	-2	-1	-3	-2	-1	-2	-1	
DIFF_HSTL_I_18_F	0.978	0.978	1.058	0.978	1.058	1.574	1.574	1.718	1.574	1.718	1.160	1.160	1.271	1.160	1.271	ns
DIFF_HSTL_I_18_S	0.978	0.978	1.058	0.978	1.058	1.805	1.805	1.950	1.805	1.950	1.748	1.748	1.867	1.748	1.867	ns
DIFF_HSTL_I_F	0.978	0.978	1.058	0.978	1.058	1.611	1.611	1.762	1.611	1.762	1.313	1.313	1.417	1.313	1.417	ns
DIFF_HSTL_I_S	0.978	0.978	1.058	0.978	1.058	1.798	1.798	1.913	1.798	1.913	1.630	1.630	1.780	1.630	1.780	ns
DIFF_HSUL_12_F	0.911	0.911	0.977	0.911	0.977	1.573	1.573	1.703	1.573	1.703	1.222	1.222	1.335	1.222	1.335	ns
DIFF_HSUL_12_S	0.911	0.911	0.977	0.911	0.977	1.711	1.711	1.864	1.711	1.864	1.536	1.536	1.665	1.536	1.665	ns
DIFF_SSTL12_F	0.906	0.906	0.977	0.906	0.977	1.643	1.643	1.792	1.643	1.792	1.285	1.285	1.423	1.285	1.423	ns
DIFF_SSTL12_S	0.906	0.906	0.977	0.906	0.977	1.784	1.784	1.948	1.784	1.948	1.567	1.567	1.706	1.567	1.706	ns
DIFF_SSTL135_F	0.927	0.927	0.995	0.927	0.995	1.625	1.625	1.765	1.625	1.765	1.341	1.341	1.458	1.341	1.458	ns
DIFF_SSTL135_II_F	0.927	0.927	0.995	0.927	0.995	1.623	1.623	1.770	1.623	1.770	1.325	1.325	1.470	1.325	1.470	ns
DIFF_SSTL135_II_S	0.927	0.927	0.995	0.927	0.995	1.768	1.768	1.916	1.768	1.916	1.722	1.722	1.911	1.722	1.911	ns
DIFF_SSTL135_S	0.927	0.927	0.995	0.927	0.995	1.869	1.869	2.025	1.869	2.025	1.814	1.814	1.976	1.814	1.976	ns
DIFF_SSTL15_F	0.928	0.928	1.020	0.928	1.020	1.628	1.628	1.771	1.628	1.771	1.374	1.374	1.483	1.374	1.483	ns
DIFF_SSTL15_II_F	0.928	0.928	1.020	0.928	1.020	1.622	1.622	1.778	1.622	1.778	1.356	1.356	1.442	1.356	1.442	ns
DIFF_SSTL15_II_S	0.928	0.928	1.020	0.928	1.020	1.821	1.821	1.987	1.821	1.987	1.895	1.895	2.047	1.895	2.047	ns
DIFF_SSTL15_S	0.928	0.928	1.020	0.928	1.020	1.824	1.824	1.977	1.824	1.977	1.743	1.743	1.907	1.743	1.907	ns
DIFF_SSTL18_II_F	0.961	0.961	1.038	0.961	1.038	1.729	1.729	1.880	1.729	1.880	1.377	1.377	1.492	1.377	1.492	ns
DIFF_SSTL18_II_S	0.961	0.961	1.038	0.961	1.038	1.796	1.796	1.965	1.796	1.965	1.616	1.616	1.800	1.616	1.800	ns
DIFF_SSTL18_I_F	0.961	0.961	1.038	0.961	1.038	1.609	1.609	1.755	1.609	1.755	1.220	1.220	1.313	1.220	1.313	ns
DIFF_SSTL18_I_S	0.961	0.961	1.038	0.961	1.038	1.786	1.786	1.942	1.786	1.942	1.677	1.677	1.836	1.677	1.836	ns
HSTL_I_18_F	0.947	0.947	1.021	0.947	1.021	1.574	1.574	1.718	1.574	1.718	1.160	1.160	1.271	1.160	1.271	ns
HSTL_I_18_S	0.947	0.947	1.021	0.947	1.021	1.805	1.805	1.950	1.805	1.950	1.748	1.748	1.867	1.748	1.867	ns

Input Delay Measurement Methodology

Table 31 shows the test setup parameters used for measuring input delay.

Table 31: **Input Delay Measurement Methodology**

Description	I/O Standard Attribute	V_L (1)(2)	V_H (1)(2)	V_{MEAS} (1)(4)(6)	V_{REF} (1)(3)(5)
LVCMOS, 1.2V	LVCMOS12	0.1	1.1	0.6	–
LVCMOS, LVDCI, HSLVDCI, 1.5V	LVCMOS15, LVDCI_15, HSLVDCI_15	0.1	1.4	0.75	–
LVCMOS, LVDCI, HSLVDCI, 1.8V	LVCMOS18, LVDCI_18, HSLVDCI_18	0.1	1.7	0.9	–
LVCMOS, 2.5V	LVCMOS25	0.1	2.4	1.25	–
LVCMOS, 3.3V	LVCMOS33	0.1	3.2	1.65	–
LVTTL, 3.3V	LVTTL	0.1	3.2	1.65	–
HSTL (high-speed transceiver logic), class I, 1.2V	HSTL_I_12	V_{REF} – 0.25	V_{REF} + 0.25	V_{REF}	0.6
HSTL, class I, 1.5V	HSTL_I	V_{REF} – 0.325	V_{REF} + 0.325	V_{REF}	0.75
HSTL, class I, 1.8V	HSTL_I_18	V_{REF} – 0.4	V_{REF} + 0.4	V_{REF}	0.9
HSUL (high-speed unterminated logic), 1.2V	HSUL_12	V_{REF} – 0.25	V_{REF} + 0.25	V_{REF}	0.6
SSTL12 (stub series terminated logic), 1.2V	SSTL12	V_{REF} – 0.25	V_{REF} + 0.25	V_{REF}	0.6
SSTL135 and SSTL135 class II, 1.35V	SSTL135, SSTL135_II	V_{REF} – 0.2875	V_{REF} + 0.2875	V_{REF}	0.675
SSTL15 and SSTL15 class II, 1.5V	SSTL15, SSTL15_II	V_{REF} – 0.325	V_{REF} + 0.325	V_{REF}	0.75
SSTL18, class I and II, 1.8V	SSTL18_I, SSTL18_II	V_{REF} – 0.4	V_{REF} + 0.4	V_{REF}	0.9
POD10, 1.0V	POD10	V_{REF} – 0.2	V_{REF} + 0.2	V_{REF}	0.7
POD12, 1.2V	POD12	V_{REF} – 0.24	V_{REF} + 0.24	V_{REF}	0.84
DIFF_HSTL, class I, 1.2V	DIFF_HSTL_I_12	0.6 – 0.25	0.6 + 0.25	0 (6)	–
DIFF_HSTL, class I, 1.5V	DIFF_HSTL_I	0.75 – 0.325	0.75 + 0.325	0 (6)	–
DIFF_HSTL, class I, 1.8V	DIFF_HSTL_I_18	0.9 – 0.4	0.9 + 0.4	0 (6)	–
DIFF_HSUL, 1.2V	DIFF_HSUL_12	0.6 – 0.25	0.6 + 0.25	0 (6)	–
DIFF_SSTL, 1.2V	DIFF_SSTL12	0.6 – 0.25	0.6 + 0.25	0 (6)	–
DIFF_SSTL135 and DIFF_SSTL135 class II, 1.35V	DIFF_SSTL135, DIFF_SSTL135_II	0.675 – 0.2875	0.675 + 0.2875	0 (6)	–
DIFF_SSTL15 and DIFF_SSTL15 class II, 1.5V	DIFF_SSTL15, DIFF_SSTL15_II	0.75 – 0.325	0.75 + 0.325	0 (6)	–
DIFF_SSTL18_I, DIFF_SSTL18_II, 1.8V	DIFF_SSTL18_I, DIFF_SSTL18_II	0.9 – 0.4	0.9 + 0.4	0 (6)	–
DIFF_POD10, 1.0V	DIFF_POD10	0.5 – 0.2	0.5 + 0.2	0 (6)	–
DIFF_POD12, 1.2V	DIFF_POD12	0.6 – 0.25	0.6 + 0.25	0 (6)	–
LVDS (low-voltage differential signaling), 1.8V	LVDS	0.9 – 0.125	0.9 + 0.125	0 (6)	–
LVDS_25, 2.5V	LVDS_25	1.25 – 0.125	1.25 + 0.125	0 (6)	–
SUB_LVDS, 1.8V	SUB_LVDS	0.9 – 0.125	0.9 + 0.125	0 (6)	–

Device Pin-to-Pin Output Parameter Guidelines

The pin-to-pin numbers in Table 40 through Table 42 are based on the clock root placement in the center of the device. The actual pin-to-pin values will vary if the root placement selected is different. Consult the Vivado Design Suite timing report for the actual pin-to-pin values.

Table 40: **Global Clock Input to Output Delay Without MMCM (Near Clock Region)**

Symbol	Description	Device	Speed Grade and V_{CCINT} Operating Voltages					Units
			0.90V	0.85V		0.72V		
			-3	-2	-1	-2	-1	
SSTL15 Global Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, *without* MMCM.								
T_{ICKOF}	Global clock input and output flip-flop *without* MMCM (near clock region).	XCKU3P	4.30	5.09	5.48	5.68	5.99	ns
		XCKU5P	4.30	5.09	5.48	5.68	5.99	ns
		XCKU9P	5.00	5.91	6.35	6.66	7.09	ns
		XCKU11P	5.82	6.96	7.61	7.19	8.36	ns
		XCKU13P	5.15	6.09	6.55	6.90	7.38	ns
		XCKU15P	5.72	6.90	7.40	7.62	8.07	ns

Notes:

1. This table lists representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible I/O and CLB flip-flops are clocked by the global clock net.

Table 41: **Global Clock Input to Output Delay Without MMCM (Far Clock Region)**

Symbol	Description	Device	Speed Grade and V_{CCINT} Operating Voltages					Units
			0.90V	0.85V		0.72V		
			-3	-2	-1	-2	-1	
SSTL15 Global Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, *without* MMCM.								
T_{ICKOF_FAR}	Global clock input and output flip-flop *without* MMCM (far clock region).	XCKU3P	4.46	5.30	5.70	5.88	6.23	ns
		XCKU5P	4.46	5.30	5.70	5.88	6.23	ns
		XCKU9P	5.38	6.49	6.97	7.14	7.59	ns
		XCKU11P	6.18	7.41	8.11	7.66	8.99	ns
		XCKU13P	5.38	6.49	6.96	7.19	7.71	ns
		XCKU15P	6.21	7.53	8.07	8.36	8.90	ns

Notes:

1. This table lists representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible I/O and CLB flip-flops are clocked by the global clock net.

Table 42: **Global Clock Input to Output Delay With MMCM**

Symbol	Description	Device	Speed Grade and V_{CCINT} Operating Voltages					Units
			0.90V	0.85V		0.72V		
			-3	-2	-1	-2	-1	
SSTL15 Global Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, with MMCM.								
$T_{ICKOFMMCMCC}$	Global clock input and output flip-flop *with* MMCM.	XCKU3P	1.98	1.98	2.17	2.66	2.66	ns
		XCKU5P	1.98	1.98	2.17	2.66	2.66	ns
		XCKU9P	2.15	2.15	2.36	2.86	2.86	ns
		XCKU11P	2.64	2.64	2.96	3.25	3.55	ns
		XCKU13P	2.18	2.18	2.38	2.88	2.90	ns
		XCKU15P	2.44	2.44	2.66	3.19	3.19	ns

Notes:

1. This table lists representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible I/O and CLB flip-flops are clocked by the global clock net in a single SLR.
2. MMCM output jitter is already included in the timing calculation.

Device Pin-to-Pin Input Parameter Guidelines

The pin-to-pin numbers in Table 43 and Table 44 are based on the clock root placement in the center of the device. The actual pin-to-pin values will vary if the root placement selected is different. Consult the Vivado Design Suite timing report for the actual pin-to-pin values.

Table 43: **Global Clock Input Setup and Hold With 3.3V HD I/O without MMCM**

Symbol	Description		Device	Speed Grade and V_{CCINT} Operating Voltages					Units
				0.90V	0.85V		0.72V		
				-3	-2	-1	-2	-1	
Input Setup and Hold Time Relative to Global Clock Input Signal using SSTL15 Standard.[(1)(2)(3)]									
T_{PSFD_KU3P}	Global clock input and input flip-flop (or latch) without MMCM.	Setup	XCKU3P	1.40	2.28	2.38	2.56	2.65	ns
T_{PHFD_KU3P}		Hold		–0.36	–0.36	–0.36	–0.15	–0.15	ns
T_{PSFD_KU5P}		Setup	XCKU5P	1.40	2.28	2.38	2.56	2.65	ns
T_{PHFD_KU5P}		Hold		–0.36	–0.36	–0.36	–0.15	–0.15	ns
T_{PSFD_KU9P}		Setup	XCKU9P	0.96	1.79	1.86	1.93	2.02	ns
T_{PHFD_KU9P}		Hold		–0.05	–0.05	–0.05	0.27	0.42	ns
T_{PSFD_KU11P}		Setup	XCKU11P	1.28	2.01	2.07	2.59	2.59	ns
T_{PHFD_KU11P}		Hold		–0.29	–0.29	–0.29	–0.09	0.19	ns
T_{PSFD_KU13P}		Setup	XCKU13P	0.96	1.79	1.85	1.92	2.01	ns
T_{PHFD_KU13P}		Hold		–0.04	–0.04	–0.04	0.27	0.43	ns
T_{PSFD_KU15P}		Setup	XCKU15P	1.41	2.29	2.38	2.57	2.65	ns
T_{PHFD_KU15P}		Hold		–0.38	–0.38	–0.38	–0.19	–0.19	ns

Notes:

1. Setup and hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the global clock input signal using the slowest process, slowest temperature, and slowest voltage. Hold time is measured relative to the global clock input signal using the fastest process, fastest temperature, and fastest voltage.
2. This table lists representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible I/O and CLB flip-flops are clocked by the global clock net in a single SLR.
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

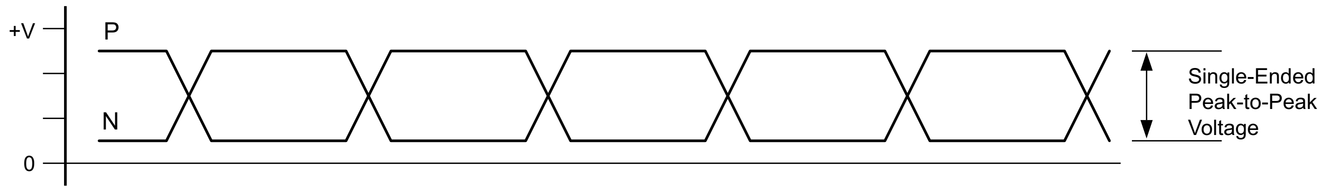

Figure 3: **Single-Ended Peak-to-Peak Voltage**

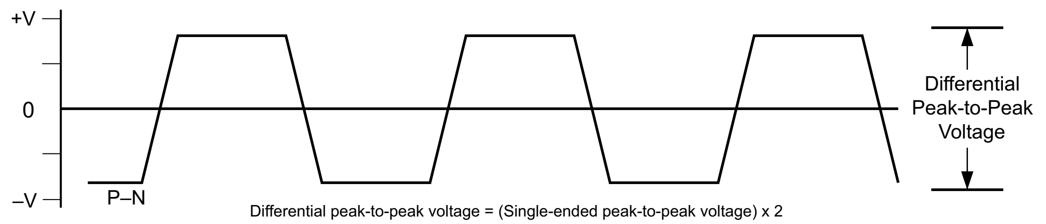

Figure 4: **Differential Peak-to-Peak Voltage**

Table 48 and Table 49 summarize the DC specifications of the GTH transceivers input and output clocks in Kintex UltraScale+ FPGAs. Consult the *UltraScale Architecture GTH Transceiver User Guide* (UG576) for further information.

Table 48: **GTH Transceiver Clock DC Input Level Specification**

Symbol	DC Parameter	Min	Typ	Max	Units
V_{IDIFF}	Differential peak-to-peak input voltage.	250	–	2000	mV
R_{IN}	Differential input resistance.	–	100	–	Ω
C_{EXT}	Required external AC coupling capacitor.	–	10	–	nF

Table 49: **GTH Transceiver Clock Output Level Specification**

Symbol	Description	Conditions	Min	Typ	Max	Units
V_{OL}	Output Low voltage for P and N.	R_T = 100Ω across P and N signals	100	–	330	mV
V_{OH}	Output High voltage for P and N.	R_T = 100Ω across P and N signals	500	–	700	mV
V_{DDOUT}	Differential output voltage. (P–N), P = High (N–P), N = High	R_T = 100Ω across P and N signals	300	–	430	mV
V_{CMOUT}	Common mode voltage.	R_T = 100Ω across P and N signals	300	–	500	mV

Table 52: **GTH Transceiver Reference Clock Switching Characteristics**

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
F_{GCLK}	Reference clock frequency range.		60	–	820	MHz
T_{RCLK}	Reference clock rise time.	20% – 80%	–	200	–	ps
T_{FCLK}	Reference clock fall time.	80% – 20%	–	200	–	ps
T_{DCREF}	Reference clock duty cycle.	Transceiver PLL only	40	50	60	%

Table 53: **GTH Transceiver Reference Clock Oscillator Selection Phase Noise Mask**

Symbol	Description	Offset Frequency	Min	Typ	Max	Units
$QPLL_{REFCLKMASK}$(1)(2)	QPLL0/QPLL1 reference clock select phase noise mask at REFCLK frequency = 312.5 MHz.	10 kHz	–	–	–105	dBc/Hz
		100 kHz	–	–	–124	
		1 MHz	–	–	–130	
$CPLL_{REFCLKMASK}$(1)(2)	CPLL reference clock select phase noise mask at REFCLK frequency = 312.5 MHz.	10 kHz	–	–	–105	dBc/Hz
		100 kHz	–	–	–124	
		1 MHz	–	–	–130	
		50 MHz	–	–	–140	

Notes:

1. For reference clock frequencies other than 312.5 MHz, adjust the phase-noise mask values by 20 x Log(N/312.5) where N is the new reference clock frequency in MHz.
2. This reference clock phase-noise mask is superseded by any reference clock phase-noise mask that is specified in a supported protocol, e.g., PCIe.

Table 54: **GTH Transceiver PLL/Lock Time Adaptation**

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
T_{LOCK}	Initial PLL lock.		–	–	1	ms
T_{DLOCK}	Clock recovery phase acquisition and adaptation time for decision feedback equalizer (DFE).	After the PLL is locked to the reference clock, this is the time it takes to lock the clock data recovery (CDR) to the data present at the input.	–	50,000	37 x 10^6	UI
	Clock recovery phase acquisition and adaptation time for low-power mode (LPM) when the DFE is disabled.		–	50,000	2.3 x 10^6	UI

Table 55: **GTH Transceiver User Clock Switching Characteristics**(1)

Symbol	Description	Data Width Conditions (Bit)		Speed Grade, Temperature Ranges, and V_{CCINT} Operating Voltages					Units
				0.90V	0.85V		0.72V		
		Internal Logic	Interconnect Logic	-3(2)	-2(2)(3)	-1(4)(5)	-2(3)	-1(3)(5)	
$F_{TXOUTPMA}$	TXOUTCLK maximum frequency sourced from OUTCLKPMA.			511.719	511.719	390.625	390.625	322.266	MHz
$F_{RXOUTPMA}$	RXOUTCLK maximum frequency sourced from OUTCLKPMA.			511.719	511.719	390.625	390.625	322.266	MHz

Table 56: **GTH Transceiver Transmitter Switching Characteristics *(Cont'd)***

Symbol	Description	Condition	Min	Typ	Max	Units
$T_{J2.5}$	Total jitter[3][4]	2.5 Gb/s[6]	–	–	0.20	UI
$D_{J2.5}$	Deterministic jitter[3][4]		–	–	0.10	UI
$T_{J1.25}$	Total jitter[3][4]	1.25 Gb/s[7]	–	–	0.15	UI
$D_{J1.25}$	Deterministic jitter[3][4]		–	–	0.06	UI
T_{J500}	Total jitter[3][4]	500 Mb/s[8]	–	–	0.10	UI
D_{J500}	Deterministic jitter[3][4]		–	–	0.03	UI

Notes:

1. Using same REFCLK input with TX phase alignment enabled for up to four consecutive transmitters (one fully populated GTH Quad) at the maximum line rate.
2. Using QPLL_FBDIV = 40, 20-bit internal data width. These values are NOT intended for protocol specific compliance determinations.
3. Using CPLL_FBDIV = 2, 20-bit internal data width. These values are NOT intended for protocol specific compliance determinations.
4. All jitter values are based on a bit-error ratio of 10^{-12}.
5. CPLL frequency at 3.2 GHz and TXOUT_DIV = 2.
6. CPLL frequency at 2.5 GHz and TXOUT_DIV = 2.
7. CPLL frequency at 2.5 GHz and TXOUT_DIV = 4.
8. CPLL frequency at 2.0 GHz and TXOUT_DIV = 8.

Table 57: **GTH Transceiver Receiver Switching Characteristics**

Symbol	Description	Condition	Min	Typ	Max	Units
F_{GTHRX}	Serial data rate		0.500	–	F_{GTHMAX}	Gb/s
R_{XSST}	Receiver spread-spectrum tracking[1]	Modulated at 33 kHz	–5000	–	0	ppm
R_{XRL}	Run length (CID)		–	–	256	UI
$R_{XPPMTOL}$	Data/REFCLK PPM offset tolerance	Bit rates ≤ 6.6 Gb/s	–1250	–	1250	ppm
		Bit rates > 6.6 Gb/s and ≤ 8.0 Gb/s	–700	–	700	ppm
		Bit rates > 8.0 Gb/s	–200	–	200	ppm
SJ Jitter Tolerance[2]						
$J_{T\_SJ16.375}$	Sinusoidal jitter (QPLL)[3]	16.375 Gb/s	0.30	–	–	UI
$J_{T\_SJ15.1}$	Sinusoidal jitter (QPLL)[3]	15.1 Gb/s	0.30	–	–	UI
$J_{T\_SJ14.1}$	Sinusoidal jitter (QPLL)[3]	14.1 Gb/s	0.30	–	–	UI
$J_{T\_SJ13.1}$	Sinusoidal jitter (QPLL)[3]	13.1 Gb/s	0.30	–	–	UI
$J_{T\_SJ12.5}$	Sinusoidal jitter (QPLL)[3]	12.5 Gb/s	0.30	–	–	UI
$J_{T\_SJ11.3}$	Sinusoidal jitter (QPLL)[3]	11.3 Gb/s	0.30	–	–	UI
$J_{T\_SJ10.32\_QPLL}$	Sinusoidal jitter (QPLL)[3]	10.32 Gb/s	0.30	–	–	UI
$J_{T\_SJ10.32\_CPLL}$	Sinusoidal jitter (CPLL)[3]	10.32 Gb/s	0.30	–	–	UI
$J_{T\_SJ9.953\_QPLL}$	Sinusoidal jitter (QPLL)[3]	9.953 Gb/s	0.30	–	–	UI
$J_{T\_SJ9.953\_CPLL}$	Sinusoidal jitter (CPLL)[3]	9.953 Gb/s	0.30	–	–	UI
$J_{T\_SJ8.0}$	Sinusoidal jitter (QPLL)[3]	8.0 Gb/s	0.42	–	–	UI
$J_{T\_SJ6.6\_CPLL}$	Sinusoidal jitter (CPLL)[3]	6.6 Gb/s	0.44	–	–	UI
$J_{T\_SJ5.0}$	Sinusoidal jitter (CPLL)[3]	5.0 Gb/s	0.44	–	–	UI
$J_{T\_SJ4.25}$	Sinusoidal jitter (CPLL)[3]	4.25 Gb/s	0.44	–	–	UI
$J_{T\_SJ3.2}$	Sinusoidal jitter (CPLL)[3]	3.2 Gb/s[4]	0.45	–	–	UI

Table 68: **GTY Transceiver Transmitter Switching Characteristics**

Symbol	Description	Condition	Min	Typ	Max	Units
F_{GTYTX}	Serial data rate range		0.500	–	F_{GTYMAX}	Gb/s
T_{RTX}	TX rise time	20%–80%	–	21	–	ps
T_{FTX}	TX fall time	80%–20%	–	21	–	ps
T_{LLSKEW}	TX lane-to-lane skew(1)		–	–	500.00	ps
$T_{J32.75}$	Total jitter(2)(4)	32.75 Gb/s	–	–	0.35	UI
$D_{J32.75}$	Deterministic jitter(2)(4)		–	–	0.19	UI
$T_{J28.21}$	Total jitter(2)(4)	28.21 Gb/s	–	–	0.28	UI
$D_{J28.21}$	Deterministic jitter(2)(4)		–	–	0.17	UI
$T_{J16.375}$	Total jitter(2)(4)	16.375 Gb/s	–	–	0.28	UI
$D_{J16.375}$	Deterministic jitter(2)(4)		–	–	0.17	UI
$T_{J15.0}$	Total jitter(2)(4)	15.0 Gb/s	–	–	0.28	UI
$D_{J15.0}$	Deterministic jitter(2)(4)		–	–	0.17	UI
$T_{J14.1}$	Total jitter(2)(4)	14.1 Gb/s	–	–	0.28	UI
$D_{J14.1}$	Deterministic jitter(2)(4)		–	–	0.17	UI
$T_{J14.1}$	Total jitter(2)(4)	14.025 Gb/s	–	–	0.28	UI
$D_{J14.1}$	Deterministic jitter(2)(4)		–	–	0.17	UI
$T_{J13.1}$	Total jitter(2)(4)	13.1 Gb/s	–	–	0.28	UI
$D_{J13.1}$	Deterministic jitter(2)(4)		–	–	0.17	UI
$T_{J12.5\_QPLL}$	Total jitter(2)(4)	12.5 Gb/s	–	–	0.28	UI
$D_{J12.5\_QPLL}$	Deterministic jitter(2)(4)		–	–	0.17	UI
$T_{J12.5\_CPLL}$	Total jitter(2)(4)	12.5 Gb/s	–	–	0.33	UI
$D_{J12.5\_CPLL}$	Deterministic jitter(2)(4)		–	–	0.17	UI
$T_{J11.3\_QPLL}$	Total jitter(2)(4)	11.3 Gb/s	–	–	0.28	UI
$D_{J11.3\_QPLL}$	Deterministic jitter(2)(4)		–	–	0.17	UI
$T_{J10.3125\_QPLL}$	Total jitter(2)(4)	10.3125 Gb/s	–	–	0.28	UI
$D_{J10.3125\_QPLL}$	Deterministic jitter(2)(4)		–	–	0.17	UI
$T_{J10.3125\_CPLL}$	Total jitter(3)(4)	10.3125 Gb/s	–	–	0.33	UI
$D_{J10.3125\_CPLL}$	Deterministic jitter(3)(4)		–	–	0.17	UI
$T_{J9.953\_QPLL}$	Total jitter(2)(4)	9.953 Gb/s	–	–	0.28	UI
$D_{J9.953\_QPLL}$	Deterministic jitter(2)(4)		–	–	0.17	UI
$T_{J9.953\_CPLL}$	Total jitter(3)(4)	9.953 Gb/s	–	–	0.33	UI
$D_{J9.953\_CPLL}$	Deterministic jitter(3)(4)		–	–	0.17	UI
$T_{J8.0}$	Total jitter(2)(4)	8.0 Gb/s	–	–	0.32	UI
$D_{J8.0}$	Deterministic jitter(2)(4)		–	–	0.17	UI
$T_{J6.6}$	Total jitter(3)(4)	6.6 Gb/s	–	–	0.30	UI
$D_{J6.6}$	Deterministic jitter(3)(4)		–	–	0.15	UI
$T_{J5.0}$	Total jitter(3)(4)	5.0 Gb/s	–	–	0.30	UI
$D_{J5.0}$	Deterministic jitter(3)(4)		–	–	0.15	UI
$T_{J4.25}$	Total jitter(3)(4)	4.25 Gb/s	–	–	0.30	UI
$D_{J4.25}$	Deterministic jitter(3)(4)		–	–	0.15	UI

Table 70: **GTY Transceiver Protocol List *(Cont'd)***

Protocol	Specification	Serial Rate (Gb/s)	Electrical Compliance
Serial RapidIO	RapidIO specification 3.1	1.25–10.3125	Compliant
DisplayPort	DP 1.2B CTS	1.62–5.4	Compliant[3]
Fibre channel	FC-PI-4	1.0625–14.025	Compliant
SATA Gen1, 2, 3	Serial ATA revision 3.0 specification	1.5, 3.0, and 6.0	Compliant
SAS Gen1, 2, 3	T10/BSR INCITS 519	3.0, 6.0, and 12.0	Compliant
SFI-5	OIF-SFI5-01.0	0.625 - 12.5	Compliant
Aurora	CEI-6G, CEI-11G-LR	All rates	Compliant

Notes:

1. 25 dB loss at Nyquist without FEC.
2. The transition time of the transmitter is faster than the IEEE Std 802.3-2012 specification.
3. This protocol requires external circuitry to achieve compliance.

Table 72: **Maximum Performance for Interlaken 6 x 25.78125 Gb/s and 6 x 28.21 Gb/s Protocol and Lane Logic Mode Designs**

Symbol	Description	Speed Grade and V_{CCINT} Operating Voltages										Units
		0.90V		0.85V				0.72V				
		-3[1]		-2[1]		-1		-2		-1		
$F_{RX\_SERDES\_CLK}$	Receive serializer/ deserializer clock	440.79		440.79		N/A		402.84		N/A		MHz
$F_{TX\_SERDES\_CLK}$	Transmit serializer/ deserializer clock	440.79		440.79		N/A		402.84		N/A		MHz
F_{DRP_CLK}	Dynamic reconfiguration port clock	250.00		250.00		N/A		250.00		N/A		MHz
		Min[2]	Max	Min[2]	Max	Min	Max	Min[2]	Max	Min	Max	
F_{CORE_CLK}	Interlaken core clock	412.50[3]	479.20	412.50[3]	479.20	N/A		412.50	429.69	N/A		MHz
F_{LBUS_CLK}	Interlaken local bus clock	300.00[4]	349.52	300.00[4]	349.52	N/A		300.00	349.52	N/A		MHz

Notes:

1. 6 x 28.21 mode is only supported in the -2 (V_{CCINT}=0.85V) and -3 (V_{CCINT}=0.90V) speed grades.
2. These are the minimum clock frequencies at the maximum lane performance.
3. The minimum value for CORE_CLK is 451.36 MHz for the 6 x 28.21 Gb/s protocol.
4. The minimum value for LBUS_CLK is 330.00 MHz for the 6 x 28.21 Gb/s protocol.

Table 73: **Maximum Performance for Interlaken 12 x 25.78125 Gb/s Lane Logic Only Mode Designs**

Symbol	Description	Speed Grade and V_{CCINT} Operating Voltages					Units
		0.90V	0.85V		0.72V		
		-3	-2	-1	-2	-1	
$F_{RX\_SERDES\_CLK}$	Receive serializer/ deserializer clock	402.84	402.84	N/A	N/A	N/A	MHz
$F_{TX\_SERDES\_CLK}$	Transmit serializer/ deserializer clock	402.84	402.84	N/A	N/A	N/A	MHz
F_{DRP_CLK}	Dynamic reconfiguration port clock	250.00	250.00	N/A	N/A	N/A	MHz
F_{CORE_CLK}	Interlaken core clock	412.50	412.50	N/A	N/A	N/A	MHz
F_{LBUS_CLK}	Interlaken local bus clock	349.52	349.52	N/A	N/A	N/A	MHz

Integrated Interface Block for 100G Ethernet MAC and PCS

More information and documentation on solutions using the integrated 100 Gb/s Ethernet block can be found at UltraScale Integrated 100G Ethernet MAC/PCS. The *UltraScale Architecture and Product Overview* (DS890) lists how many blocks are in each Kintex UltraScale+ FPGA.

Table 74: **Maximum Performance for 100G Ethernet Designs**

Symbol	Description	Speed Grade and V_{CCINT} Operating Voltages					Units
		0.90V	0.85V		0.72V		
		-3	-2[1]	-1	-2	-1[2]	
F_{TX_CLK}	Transmit clock	390.625	390.625	322.223	322.223	322.223	MHz
F_{RX_CLK}	Receive clock	390.625	390.625	322.223	322.223	322.223	MHz
$F_{RX\_SERDES\_CLK}$	Receive serializer/deserializer clock	390.625	390.625	322.223	322.223	322.223	MHz
F_{DRP_CLK}	Dynamic reconfiguration port clock	250.00	250.00	250.00	250.00	250.00	MHz

Notes:

1. The maximum clock frequency of 390.625 MHz only applies to the CAUI-10 interface. The maximum clock frequency for the CAUI-4 interface is 322.223 MHz.
2. The CAUI-4 interface is not supported by -1L speed grade devices where V_{CCINT}=0.72V.

Integrated Interface Block for PCI Express Designs

More information and documentation on solutions for PCI Express designs can be found at PCI Express. The *UltraScale Architecture and Product Overview* (DS890) lists how many blocks are in each Kintex UltraScale+ FPGA.

Table 75: **Maximum Performance for PCI Express Designs[1][2]**

Symbol	Description	Speed Grade and V_{CCINT} Operating Voltages					Units
		0.90V	0.85V		0.72V		
		-3	-2	-1	-2	-1	
$F_{PIPECLK}$	Pipe clock maximum frequency.	250.00	250.00	250.00	250.00	250.00	MHz
$F_{CORECLK}$	Core clock maximum frequency.	500.00	500.00	500.00	250.00	250.00	MHz
F_{DRPCLK}	DRP clock maximum frequency.	250.00	250.00	250.00	250.00	250.00	MHz
$F_{MCAPCLK}$	MCAP clock maximum frequency.	125.00	125.00	125.00	125.00	125.00	MHz

Notes:

1. PCI Express Gen4 operation is supported for x1, x2, x4, and x8 widths.
2. PCI Express Gen4 operation is supported in -3E, -2E, and -2I speed grades.

Table 79: **Configuration Switching Characteristics *(Cont'd)***

Symbol	Description		0.90V -3	0.85V -2	0.85V -1	0.72V -2	0.72V -1	Units
SelectMAP Mode Programming Switching								
T_{SMDCCK}/T_{SMCCKD}	D[31:00] setup/hold.	XCKU3P, XCKU5P	4.5/0	4.5/0	4.5/0	8.0/0	8.0/0	ns, Min
		All other devices	3.5/0	3.5/0	3.5/0	4.5/0	4.5/0	
$T_{SMCSCCK}/T_{SMCCKCS}$	CSI_B setup/hold.	XCKU3P, XCKU5P	4.5/0	4.5/0	4.5/0	7.0/0	7.0/0	ns, Min
		All other devices	4.0/0	4.0/0	4.0/0	5.0/0	5.0/0	
T_{SMWCCK}/T_{SMCCKW}	RDWR_B setup/hold.	XCKU3P, XCKU5P	10.0/0	10.0/0	10.0/0	17.0/0	17.0/0	ns, Min
		All other devices	10.0/0	10.0/0	10.0/0	11.0/0	11.0/0	
$T_{SMCKCSO}$	CSO_B clock to out (330Ω pull-up resistor required).	XCKU3P, XCKU5P	7.0	7.0	7.0	10.0	10.0	ns, Max
		All other devices	7.0	7.0	7.0	7.0	7.0	
T_{SMCO}	D[31:00] clock to out in readback.	XCKU3P, XCKU5P	8.0	8.0	8.0	10.0	10.0	ns, Max
		All other devices	8.0	8.0	8.0	8.0	8.0	
F_{RBCCK}	Readback frequency.	XCKU3P, XCKU5P	125	125	125	60	60	MHz, Max
		All other devices	125	125	125	125	125	
Boundary-Scan Port Timing Specifications								
T_{TAPTCK}/T_{TCKTAP}	TMS and TDI setup/hold.		3.0/ 2.0	3.0/ 2.0	3.0/ 2.0	3.0/ 2.0	3.0/ 2.0	ns, Min
T_{TCKTDO}	TCK falling edge to TDO output.		7.0	7.0	7.0	7.0	7.0	ns, Max
F_{TCK}	TCK frequency.	XCKU15P	66	66	66	50	50	MHz, Max
		All other devices	66	66	66	66	66	
BPI Master Flash Mode Programming Switching								
T_{BPICCO}	A[28:00], RS[1:0], FCS_B, FOE_B, FWE_B, ADV_B clock to out.		10	10	10	10	10	ns, Max
T_{BPIDCC}/T_{BPICCD}	D[15:00] setup/hold.	XCKU3P, XCKU5P	4.5/0	4.5/0	4.5/0	8.0/0	8.0/0	ns, Min
		All other devices	3.5/0	3.5/0	3.5/0	4.5/0	4.5/0	
SPI Master Flash Mode Programming Switching								
T_{SPIDCC}/T_{SPICCD}	D[03:00] setup/hold.		3.0/0	3.0/0	3.0/0	4.0/0	4.0/0	ns, Min
T_{SPIDCC}/T_{SPICCD}	D[07:04] setup/hold.	XCKU3P, XCKU5P	4.5/0	4.5/0	4.5/0	8.0/0	8.0/0	ns, Min
		All other devices	3.5/0	3.5/0	3.5/0	4.5/0	4.5/0	
T_{SPICCM}	MOSI clock to out.		8.0	8.0	8.0	8.0	8.0	ns, Max
$T_{SPICCFC}$	FCS_B clock to out.		8.0	8.0	8.0	8.0	8.0	ns, Max
DNA Port Switching								
F_{DNACK}	DNA port frequency.		200	200	200	175	175	MHz, Max
STARTUPE3 Ports								
$T_{USRCCLKO}$	STARTUPE3 USRCCLKO input port to CCLK pin output delay.		0.25/ 6.00	0.25/ 6.50	0.25/ 7.50	0.25/ 9.00	0.25/ 9.00	ns, Min/Max
T_{DO}	DO[3:0] ports to D03-D00 pins output delay.		0.25/ 6.70	0.25/ 7.70	0.25/ 8.40	0.25/ 10.00	0.25/ 10.00	ns, Min/Max
T_{DTS}	DTS[3:0] ports to D03-D00 pins 3-state delays.		0.25/ 6.70	0.25/ 7.70	0.25/ 8.40	0.25/ 10.00	0.25/ 10.00	ns, Min/Max

Speed Grade and V_{CCINT} Operating Voltages apply to columns 0.90V (-3), 0.85V (-2, -1), 0.72V (-2, -1).

Revision History

The following table shows the revision history for this document.

Date	Version	Description of Revisions
04/11/2017	1.2	Updated the Summary description. In Table 1, updated and added data, and updated Note 7, added Note 8, Note 9, and Note 10. Updated and added data to Table 2, revised Note 11 and added Note 12 and Note 13. Updated Table 3 and added Note 6. Added specifications to Table 4 though Table 6. Updated maximum V_{ICM} and Note 1 in Table 18. Updated the maximum V_{ODIFF} in Table 19. Updated Table 20, Table 21, and Table 22 to production release for the following devices/speed/temperature grades in Vivado Design Suite 2017.1. XCKU3P: -2E, -2I, -1E, -1I XCKU5P: -2E, -2I, -1E, -1I Added Note 1 to Table 21. Updated Table 23. Updated Table 24 and added Note 2. Added Table 25. Updated Table 27 and added Note 3. Many revisions to the speed specifications in Table 28, Table 29, Table 30, Table 33, Table 34, Table 35, Table 40, Table 41, Table 42, Table 43, Table 44, and Table 45. Updated V_L and V_H values in Table 31. In Table 35, added T_{MINPER_CLK} and Note 1, and revised F_{REFCLK}. Added $MMCM\_F_{DPRCLK\_MAX}$ to Table 38 and $PLL\_F_{DPRCLK\_MAX}$ to Table 39. Updated Table 46. Revised the GTH Transceiver Specifications and GTH Transceiver Specifications sections. Revised the Integrated Interface Block for Interlaken and Integrated Interface Block for 100G Ethernet MAC and PCS sections. Updated the System Monitor Specifications section including On-Chip Sensor Accuracy and adding Note 3 to Table 76. Removed timing diagrams from the SYSMON I2C/PMBus Interfaces section. Updated the Configuration Switching Characteristics section. Removed the *eFUSE Programming Conditions* table and added the specifications to Table 2 and Table 3. Updated Table 79. Updated the Automotive Applications Disclaimer.
05/09/2016	1.1	In Table 1 revised V_{IN} for HP I/O banks. Updated Note 5 in Table 3. Added values to Table 7. Added MIPI_DPHY_DCI to Table 9, Table 10, and Table 12. Updated and added notes in Table 18 and Table 19. Updated Table 20 speed specifications for Vivado Design Suite 2016.1. Removed Table 23, *Video Codec Unit Performance*. Updated Table 24. Expanded and updated Table 27. Updated Table 28 and Table 29. Updated Table 31 and Table 32 with MIPI D-PHY values. Updated Table 31 and Table 32. In Table 33, added the Block RAM and FIFO Clock-to-Out Delays section. Updated Table 40 to Table 44. Revised the symbol names in Table 43. Revised typical values in Table 48. Updated the -2 (0.72V) and -1 (0.72V) values in Table 50. Added Table 53 and Table 65. Added Note 2 to Table 59. Revised Table 67. Revised data and added notes to Table 62, Table 71, and Table 74. Revised INL in Table 76. Added notes to Table 77 and Table 78. Many revised sections in Table 79.
11/24/2015	1.0	Initial Xilinx release.